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Substitute	e for form 1449/P	Substitute for form 1449/PTO			Complete if Known		
Substitute for form 14401 15				Application Number	10/812,177-Conf. #3379		
INF	INFORMATION DISCLOSURE			Filing Date	March 29, 2004		
STA	TEMEN	T BY	APPLICANT	First Named Inventor	Keisuke inoue		
		, _ ,		Art Unit	2128		
(Use as many sheets as necessary)		Examiner Name	S. A. Alhija				
Sheet	1	of	1	Attorney Docket Number	SCEI 3.0-170		

U.S. PATENT DOCUMENTS						
Examiner	Cite	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant	
tnitials*	No.1		MM-DD-YYYY	Applicant of Cited Document	Figures Appear	
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		FOREIG	ON PATENT	DOCUMENTS		
F	0:44	Foreign Patent Document	Publication	Name of Patentee or	Pages, Cotumns, Lines, Where Relevant Passages	_
Examiner Initiats*	Cite No.1	Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Date MM-DD-YYYY	Applicant of Cited Document	Or Relevant Figures Appear	To
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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Examiner	(5. 11)	Date	1/31/08	
Signature		Considered	1 15.7 - 0	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 1

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Examiner Initials*	Cite No.1	Number-Kind Code ² (if known)	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear	
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S	ВА	EP-1096360	05-02-2001	Texas Instruments Incorporated		

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Ø	CA	ANOOP IYER, DIANA MARCULESCU: "Power Aware Microarchitecture Resource Scaling" Design, Automation and Test in Europe, Conference and Exhibition March 13, 2001, pp. 190-196 (7 pages).			
(P	СВ	Taku, Yasui "Linux Kernel for beginners, Part 3, Processing scheduling", Nikkei Linux, Nikkei BP, November 8, 2003, Vol. 5, No. 11, pp. 97-103 (CS-ND-2004-01116-007)			

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